

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L2	53076	optical and (test\$3 or probe) and (wafer or ic)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:30
L3	4958	I2 and transducer	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:31
L4	1350	I3 and led	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:31
L5	27	I4 and (test adj point)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:34
L6	57	circuit\$3 and test3\$ and optical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:38
L7	0	(integrated adj circuit) and wafer and test3\$ and optical	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:39
L8	0	(integrated adj circuit) and wafer and test3\$ and led	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:39
L9	38	(integrated adj circuit) and wafer and (test adj point) and led	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/09/22 09:39